捷多邦,专业PCB打样**SN654B017**高出**SN75LBC171**TRIPLE DIFFERENTIAL TRANSCEIVERS

SLLS460A - NOVEMBER 2000 - REVISED FEBRUARY 2001

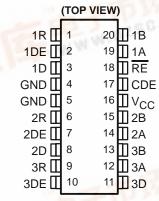
- Three Differential Transceivers in One Package
- Signaling Rates¹ Up to 30 Mbps
- Low Power and High Speed
- Designed for TIA/EIA-485, TIA/EIA-422, ISO 8482, and ANSI X3.277 (HVD SCSI Fast–20) Applications
- Common-Mode Bus Voltage Range
 7 V to 12 V
- ESD Protection on Bus Terminals Exceeds 12 kV
- Driver Output Current up to ±60 mA
- Thermal Shutdown Protection
- Driver Positive and Negative Current Limiting
- Power-Up, Power-Down Glitch-Free Operation
- Pin-Compatible With the SN75ALS171
- Available in Shrink Small-Outline Package

description

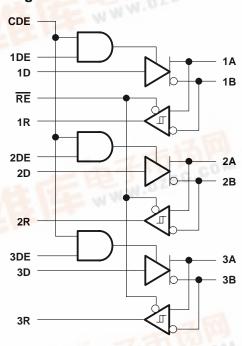
The SN65LBC171 and SN75LBC171 are monolithic integrated circuits designed for bidirectional data communication on multipoint bus-transmission lines. Potential applications include serial or parallel data transmission, cabled peripheral buses with twin axial, ribbon, or twisted-pair cabling. These devices are suitable for FAST–20 SCSI and can transmit or receive data pulses as short as 25 ns, with skew less than 3 ns.

These devices combine three 3-state differential line drivers and three differential input line receivers, all of which operate from a single 5-V power supply.

SN65LBC171DB (Marked as BL171) SN75LBC171DB (Marked as LB171) SN65LBC171DW (Marked as 65LBC171) SN75LBC171DW (Marked as 75LBC171)



logic diagram



The driver differential outputs and the receiver differential inputs are connected internally to form three differential input/output (I/O) bus ports that are designed to offer minimum loading to the bus whenever the driver is disabled or $V_{CC} = 0$. These ports feature a wide common-mode voltage range making the device suitable for party-line applications over long cable runs.

The SN75LBC171 is characterized for operation over the temperature range of 0°C to 70°C. The SN65LBC171 is characterized for operation over the temperature range of –40°C to 85°C.

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

The signaling rate of a line is the number of voltage transitions that are made per second expressed in the units bps (bits per second).



AVAILABLE OPTIONS[†]

	PACKAGE PLASTIC SMALL-OUTLINE (JEDEC MS-013) PLASTIC SHRINK SMALL-OUTLINE (JEDEC MO-150)				
TA					
0°C to 70°C	SN75LBC171DW	SN75LBC171DB			
-40°C to 85°C	SN65LBC171DW	SN65LBC171DB			

[†] Add R suffix for taped and reel

Function Tables

EACH DRIVER

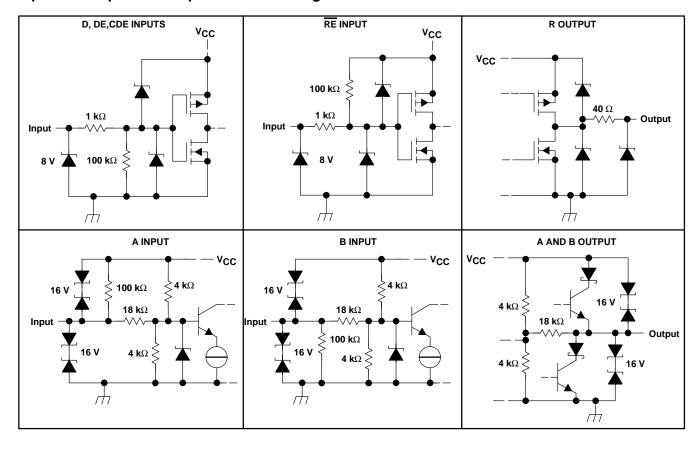
INPUT	ENABLE		OUT	PUTS
D	DE	CDE	Α	В
Н	Н	Н	Н	L
L	Н	Н	L	Н
OPEN	Н	Н	L	Н
Х	L	Χ	Z	Z
Х	Х	L	Z	Z
X	OPEN	Χ	Z	Z
Х	Х	OPEN	Z	Z

EACH RECEIVER

DIFFERENTIAL INPUT (VA-VB)	ENABLE RE	OUTPUT R
V _{ID} ≥ 0.2 V	L	Н
-0.2 V < V _{ID} < 0.2 V	L	?
$V_{ID} \le -0.2 V$	L	L
X	Н	Z
OPEN	L	Н

H = high level, L = low level, X = irrelevant, Z = high impedance (off), ? = indeterminate

equivalent input and output schematic diagrams



SN65LBC171, SN75LBC171 TRIPLE DIFFERENTIAL TRANSCEIVERS

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absolute maximum ratings†

Supply voltage, V _{CC} (see Note 1)	
Voltage range at any bus I/O terminal (steady state)	
Voltage input range, A and B, (transient pulse through 100 Ω , see Figure	
Voltage range at any DE, RE, or CDE terminal	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Electrostatic discharge: Human body model (A, B, GND) (see Note 2)	12 kV
All pins	5 kV
Charged-device model (all pins) (see Note 3) .	1 kV
Continuous total power dissipation	See Power Dissipation Rating Table
Storage temperature range, T _{Stq}	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values, except differential I/O bus voltages, are with respect to network ground terminal.

- 2. Tested in accordance with JEDEC Standard 22, Test Method A114-A.
- 3. Tested in accordance with JEDEC Standard 22, Test Method C101.

POWER DISSIPATION RATING TABLE

PACKAGE	$T_{\mbox{A}} \le 25^{\circ}\mbox{C}$ POWER RATING	DERATING FACTOR‡ ABOVE T _A = 25°C	T _A = 70°C POWER RATING	T _A = 85°C POWER RATING
DB	995 mW	8.0 mW/°C	635 mW	515 mW
DW	1480 mW	11.8 mW/°C	950 mW	770 mW

[‡] This is the inverse of the junction-to-ambient thermal resistance when board-mounted and with no air flow.

recommended operating conditions

		MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}		4.75	5	5.25	V
Voltage at any bus I/O terminal	A, B	-7		12	V
High-level input voltage, VIH	DE, CDE, RE	2		VCC	V
Low-level input voltage, V _{IL}	DE, CDE, RE	0		0.8	V
Differential input voltage, V _{ID}	A with respect to B	-12		12	V
Outrout augment	Driver	-60		60	A
Output current	Receiver	-8		8	mA
Operating free-air temperature, T _A	SN75LBC171	0		70	°C
	SN65LBC171	-40		85	°C

SN65LBC171, SN75LBC171 TRIPLE DIFFERENTIAL TRANSCEIVERS

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DRIVER SECTION

electrical characteristics over recommended operating conditions

	PARAMETER		ONDITIONS	MIN	TYP†	MAX	UNIT	
VIK	Input clamp voltage D, DE, CDE	I _I = 18 mA		-1.5	-0.7		V	
VO	Open-circuit output voltage (single-ended)	A or B, No load		0		VCC	V	
	.	No load		3.8	4.3	VCC	V	
VOD(SS)	Steady-state differential output voltage magnitude‡	$R_L = 54 \Omega$,	See Figure 1	1	1.6	2.4	V	
	magnitude+	With common-mode	loading, See Figure 2	1	1.6	2.4	V	
ΔV _{OD}	Change in differential output voltage magnitude, $ V_{OD(H)} - V_{OD(L)} $			-0.2		0.2	V	
Voc(ss)	Steady-state common-mode output voltage	$R_L = 54 \Omega$, $C_L = 50 \text{ pF}$	$R_L = 54 \Omega$, $C_L = 50 \text{ pF}$	See Figure 1	2	2.4	2.8	V
Δ VOC(SS)	Change in steady-state common-mode output voltage (V _{OC} (H) - V _{OC} (L))			-0.2		0.2	V	
Ц	Input current	D, DE, CDE		-100		100	μΑ	
IO	Output current with power off	$V_{CC} = 0 V$,	$V_0 = -7 \text{ V to } 12 \text{ V}$	-700		900	μΑ	
los	Short-circuit output current	$V_0 = -7 \text{ V to } 12 \text{ V},$	See Figure 7	-250		250	mA	
ICC	Supply current (driver enabled)	D at 0 V or V _{CC} ,	CDE, DE, RE at V _{CC} , No load		14	20	mA	

[†] All typical values are at $V_{CC} = 5 \text{ V}$ and $T_A = 25^{\circ}\text{C}$.

switching characteristics over recommended operating conditions

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
^t PLH	Differential output propagation delay, low-to high		4	8.5	12	
^t PHL	Differential output propagation delay, high-to-low	7	4	8.5	11	
t _r	Differential output rise time		3	7.5	11	
tf	Differential output fall time	$R_L = 54 \Omega$, $C_L = 50 pF$, See Figure 3	3	7.5	11	ns
t _{sk(p)}	Pulse skew (tpLH - tpHL)	Occ rigure 3			2	
tsk(o)	Output skew§	1			1.5	
tsk(pp)	Part-to-part skew¶				2	
^t PLH	Differential output propagation delay, low-to high	-	3	7	10	
^t PHL	Differential output propagation delay, high-to-low		3	7.5	10	
t _r	Differential output rise time	7,	3	7.5	12	
t _f	Differential output fall time	See Figure 4, (HVD SCSI double-terminated load)	3	7.5	12	ns
tsk(p)	Pulse skew (tpLH - tpHL)	(TVD GGGI dodbie terminated load)			3	
tsk(o)	Output skew§	7			1.5	
tsk(pp)	Part-to-part skew¶	7			2.5	
^t PZH	Output enable time to high level	See Figure 5		15	25	
^t PHZ	Output disable time from high level			18	25	ns
tPZL	Output enable time to low level	See Figure 6		10	25	
^t PLZ	Output disable time from low level	See Figure 6		17	25	ns

[§] Output skew $(t_{sk(0)})$ is the magnitude of the time delay difference between the outputs of a single device with all of the inputs connected together. Part-to-part skew $(t_{sk(pp)})$ is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same input signals, the same supply voltages, at the same temperature, and have identical packages and test circuits.



[‡] The minimum V_{OD} may not fully comply with TIA/EIA-485-A at operating temperatures below 0°C. System designers should take the possibly lower output signal into account in determining the maximum signal-transmission distance.

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RECEIVER SECTION

electrical characteristics over recommended operating conditions

	PARAMETER	TEST CO	NDITIONS	MIN	TYP [†]	MAX	UNIT
V _{IT+}	Positive-going differential input voltage threshold					0.2	V
V _{IT} _	Negative-going differential input voltage threshold			-0.2			V
V _{hys}	Hysteresis voltage (V _{IT+} – V _{IT} _)				40		mV
Vон	High-level output voltage	V_{ID} = 200 mV, I_{OH} = -8 mA, see Figure 10		4	4.7	VCC	V
VOL	Low-level output voltage	$V_{ID} = -200$ mV, $I_{OL} =$	–8 mA, see Figure 10	0	0.2	0.4	V
	Line input ourrent	Other innut 01/	V _I = 12 V			0.9	A
'	Line input current	Other input = 0 V	V _I = −7 V	-0.7			mA
Ιį	Input current	RE		-100		100	μΑ
R _I	Input resistance	А, В		12			kΩ
Icc	Supply current (receiver enabled)	A, B, D open, RE, D	DE, and CDE at 0 V			16	mA

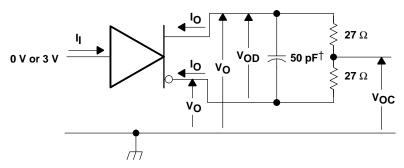
[†] All typical values are at $V_{CC} = 5 \text{ V}$ and $T_A = 25^{\circ}\text{C}$.

switching characteristics over recommended operating conditions

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
^t PLH	Propagation delay time, low-to-high level output		7		16	ns
tPHL	Propagation delay time, high-to-low level output	V _{ID} = −3 V to 3 V, See Figure 9	7		16	ns
t _r	Receiver output rise time			1.3	3	ns
t _f	Receiver output fall time			1.3	3	ns
^t PZH	Receiver output enable time to high level	See Figure 10		26	40	no
^t PHZ	Receiver output disable time from high level	See Figure 10			40	ns
^t PZL	Receiver output enable time to low level	See Figure 11		29	40	ns
^t PLZ	Receiver output enable time to high level	See Figure 11			40	115
t _{sk(p)}	Pulse skew ((t _{PLH} - t _{PHL})				2	ns
t _{sk(o)}	Output skew [‡]				1.5	ns
tsk(pp)	Part-to-part skew§				3	ns

[‡] Output skew (t_{sk(o)}) is the magnitude of the time delay difference between the outputs of a single device with all of the inputs connected together. § Part-to-part skew (t_{sk(pp)}) is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same input signals, the same supply voltages, at the same temperature, and have identical packages and test circuits.





†Includes probe and jig capacitance

Figure 1. Driver Test Circuit, V_{OD} and V_{OC} Without Common-Mode Loading

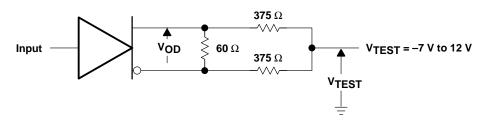
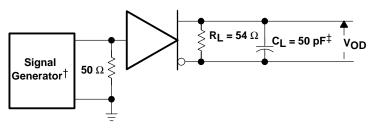


Figure 2. Driver Test Circuit, $V_{\mbox{\scriptsize OD}}$ With Common-Mode Loading



† PRR = 1 MHz, 50% Duty Cycle, $\rm t_f$ < 6 ns, $\rm t_f$ < 6 ns, $\rm Z_O$ = 50 $\rm \Omega$ ‡ Includes Probe and Jig Capacitance

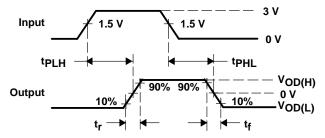
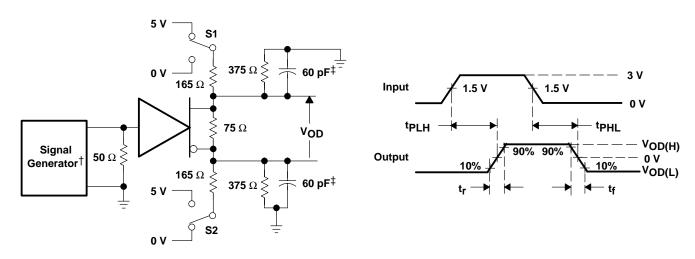


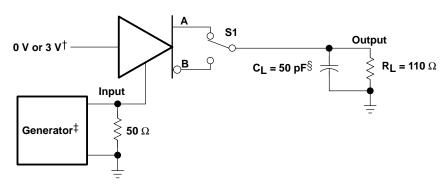
Figure 3. Driver Switching Test Circuit and Waveforms, 485-Loading





- † PRR = 1 MHz, 50% Duty Cycle, t_{f} < 6 ns, t_{f} < 6 ns, Z_{O} = 50 Ω
- ‡ Includes Probe and Jig Capacitance

Figure 4. Driver Switching Test Circuit and Waveforms, HVD SCSI-Loading (double terminated)



- † 3 V if testing A output, 0 V if testing B output
- ‡ PRR = 1 MHz, 50% Duty Cycle, $t_r < 6$ ns, $t_f < 6$ ns, $Z_0 = 50 \Omega$
- § Includes Probe and Jig Capacitance

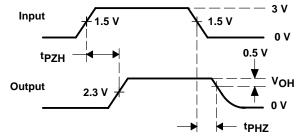
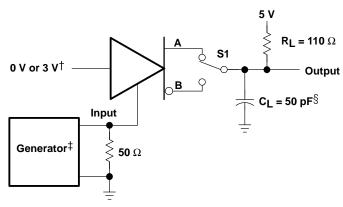
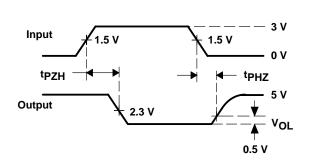


Figure 5. Driver Enable/Disable Test, High Output





- † 0 V if testing A output, 3 V if testing B output
- ‡ PRR = 1 MHz, 50% Duty Cycle, t_r < 6 ns, t_f < 6 ns, Z_O = 50 Ω
- § Includes Probe and Jig Capacitance

Figure 6. Driver Enable/Disable Test, Low Output

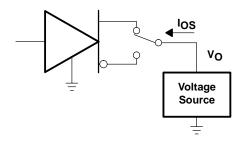


Figure 7. Driver Short-Circuit Test

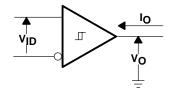
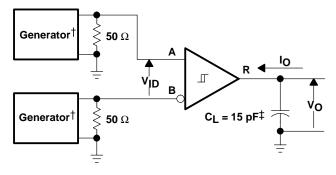
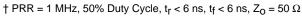


Figure 8. Receiver DC Parameters





‡ Includes Probe and Jig Capacitance

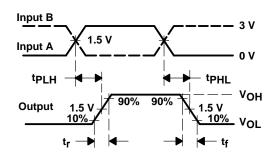
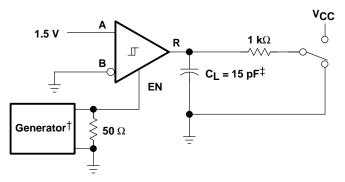
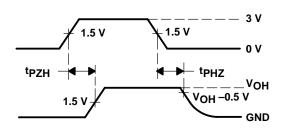


Figure 9. Receiver Switching Test Circuit and Waveforms

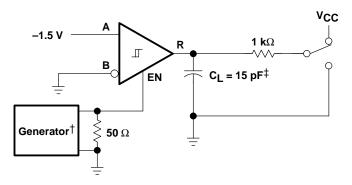


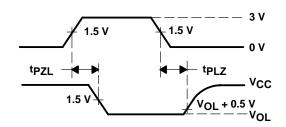




- † PRR = 1 MHz, 50% Duty Cycle, $t_{\rm f}$ < 6 ns, $t_{\rm f}$ < 6 ns, $Z_{\rm O}$ = 50 Ω
- ‡ Includes Probe and Jig Capacitance

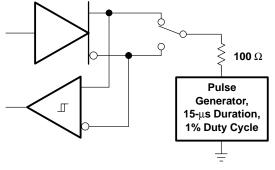
Figure 10. Receiver Enable/Disable Test, High Output





- † PRR = 1 MHz, 50% Duty Cycle, t_{f} < 6 ns, t_{f} < 6 ns, Z_{O} = 50 Ω
- ‡ Includes Probe and Jig Capacitance

Figure 11. Receiver Enable/Disable Test, Low Output



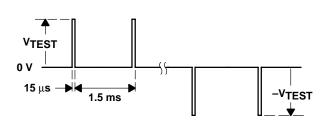
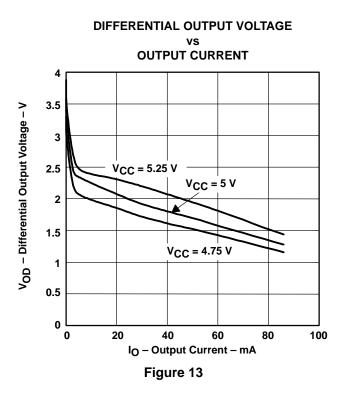
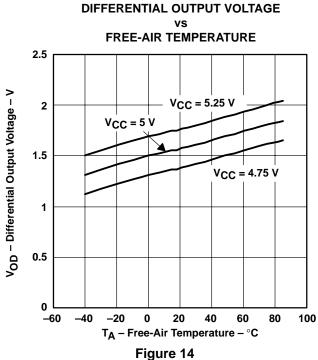
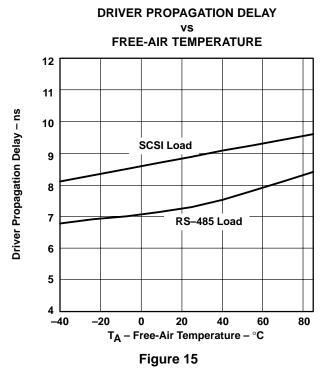
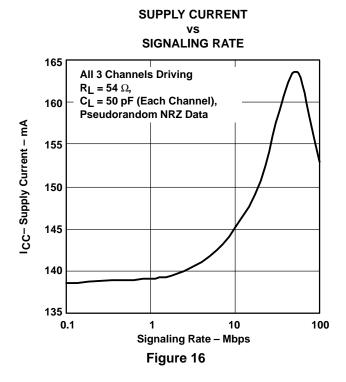


Figure 12. Test Circuit and Waveform, Transient Over Voltage Test









TEXAS

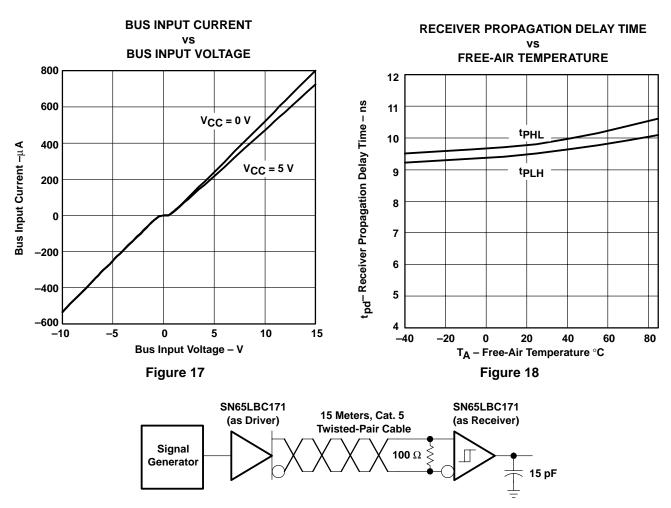


Figure 19. Circuit Diagram for Signaling Characteristics

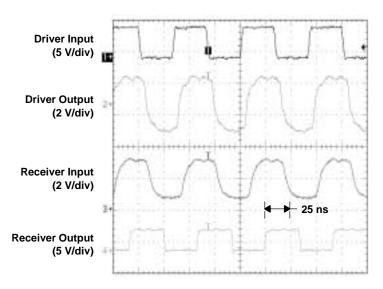


Figure 20. Signal Waveforms at 30 Mbps

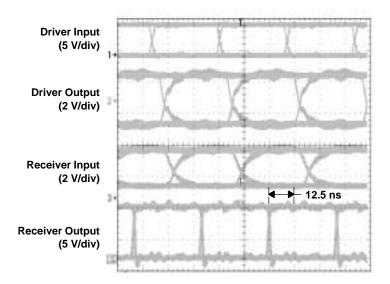


Figure 21. Eye Patterns, Pseudorandom Data at 30 Mbps

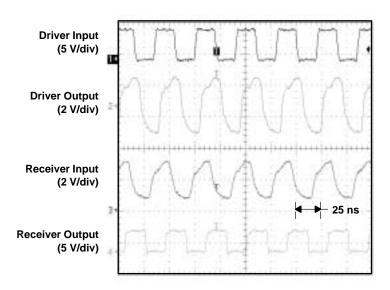


Figure 22. Signal Waveforms at 50 Mbps

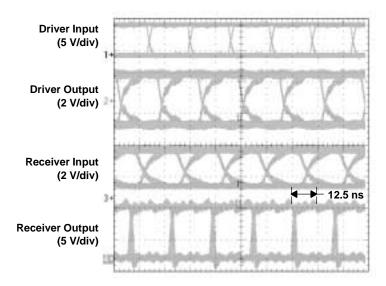


Figure 23. Eye Patterns, Pseudorandom Data at 50 Mbps

SN65LBC171, SN75LBC171 TRIPLE DIFFERENTIAL TRANSCEIVERS

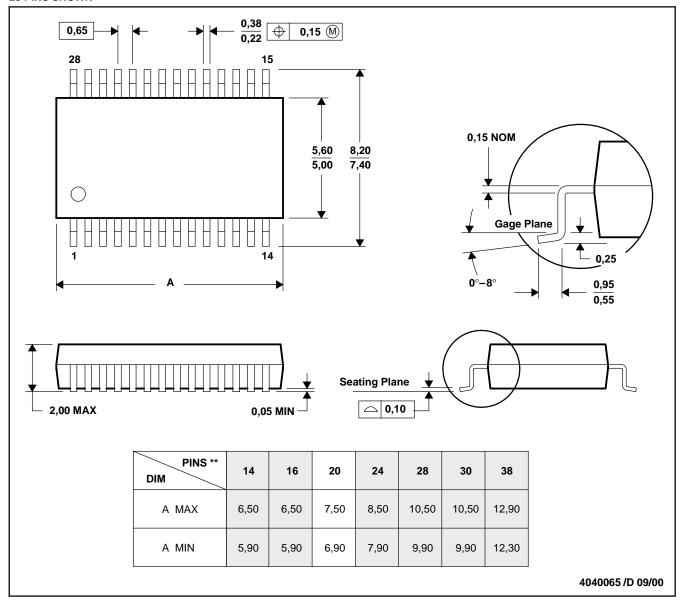
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MECHANICAL DATA

DB (R-PDSO-G**)

PLASTIC SMALL-OUTLINE

28 PINS SHOWN



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-150



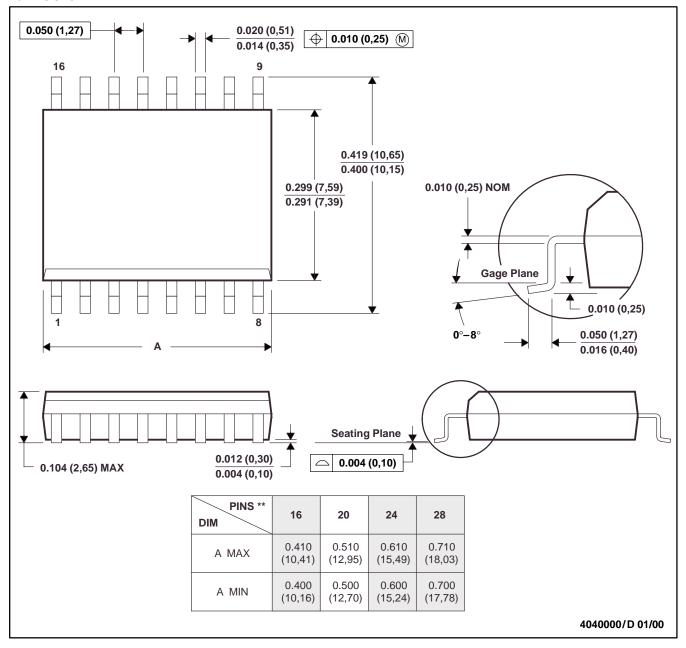
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MECHANICAL DATA

DW (R-PDSO-G**)

16 PINS SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013



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